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(12) **United States Design Patent**  
**Treibergs et al.**

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(54) **COMPLIANT GROUND BLOCK AND TESTING SYSTEM FOR TESTING INTEGRATED CIRCUITS**

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(\*\*) Term: **15 Years**

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(22) Filed: **Jan. 19, 2021**

*Primary Examiner* — Mark A Goodwin

(51) **LOC (14) Cl.** ..... **13-03**

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(52) **U.S. Cl.**

(74) *Attorney, Agent, or Firm* — HSML P.C.

USPC ..... **D13/182**

(58) **Field of Classification Search**

(57) **CLAIM**

USPC ..... D13/117, 121, 133, 164, 173, 182, 184,  
D13/199

The ornamental design for a compliant ground block and testing system for testing integrated circuits, as shown and described.

CPC ..... H05K 3/36; H05K 3/361; H05K 3/363;  
H05K 3/365; H05K 3/40; H05K 3/4007;  
H05K 4/4015

See application file for complete search history.

**DESCRIPTION**

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FIG. 1 is a Top Perspective view of a compliant ground block and testing system for testing integrated circuits showing the new design;

FIG. 2 is a Bottom Perspective view thereof;

FIG. 3 is a Front view thereof;

FIG. 4 is a Back view thereof;

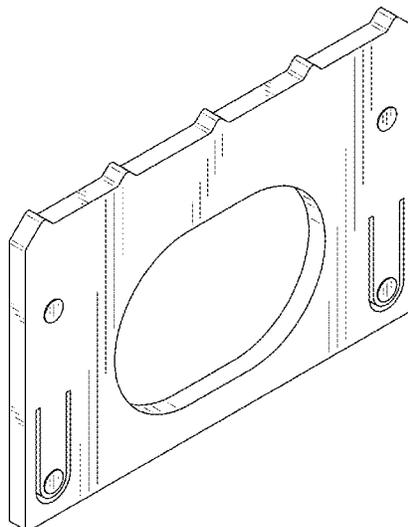
FIG. 5 is a Left view thereof;

FIG. 6 is a Right view thereof;

FIG. 7 is a Top view thereof; and,

FIG. 8 is a Bottom view thereof.

**1 Claim, 5 Drawing Sheets**



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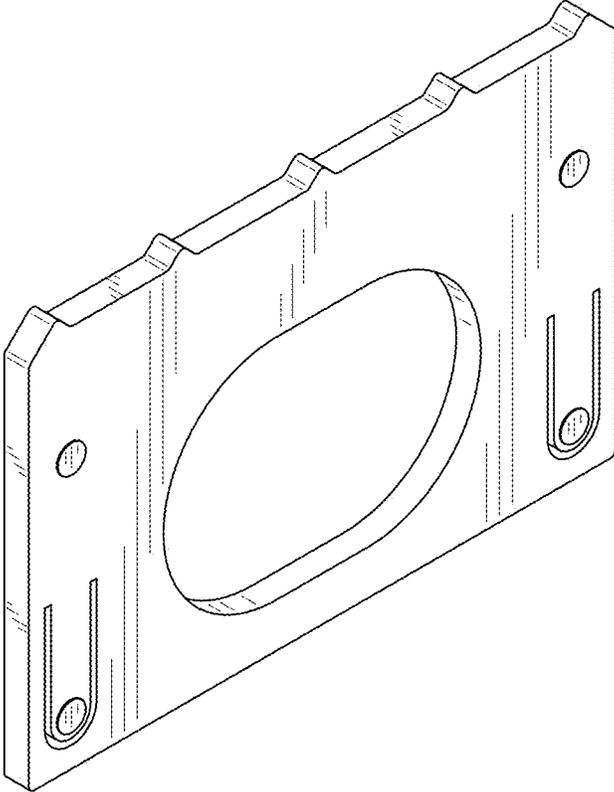


FIG. 1

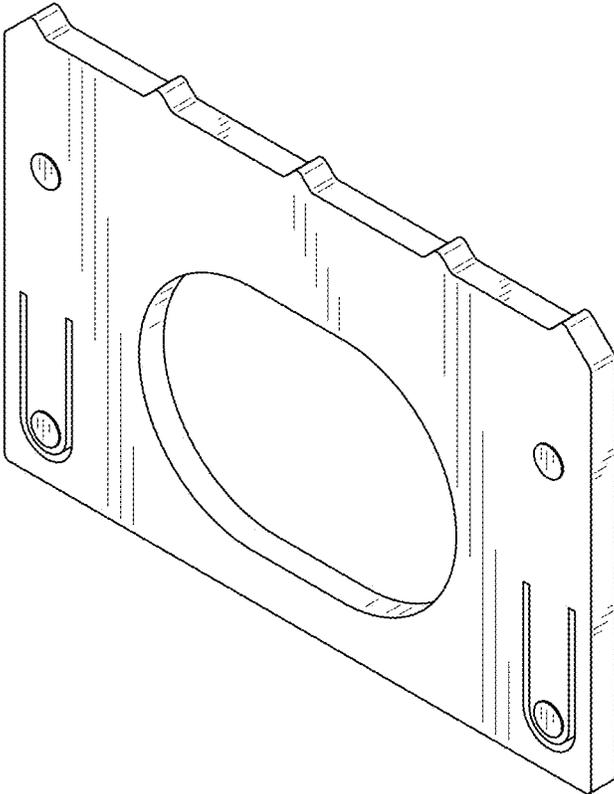


FIG. 2

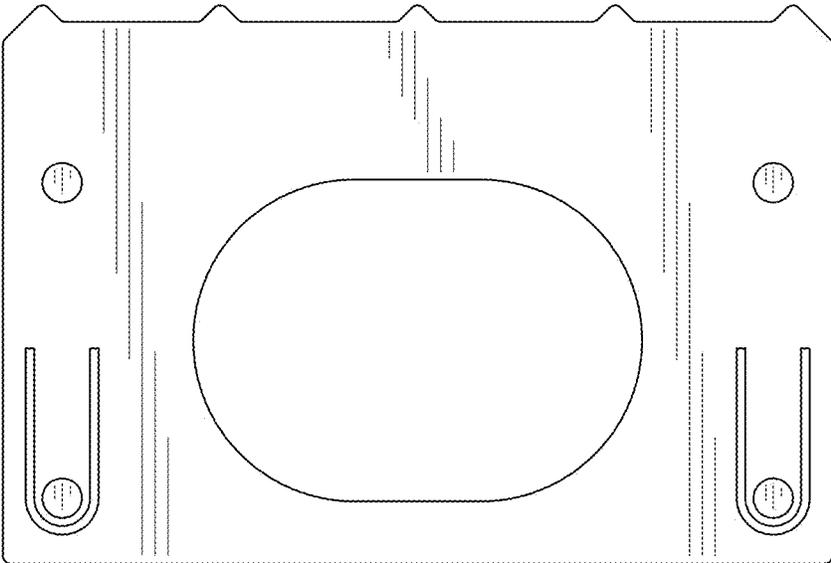


FIG. 3

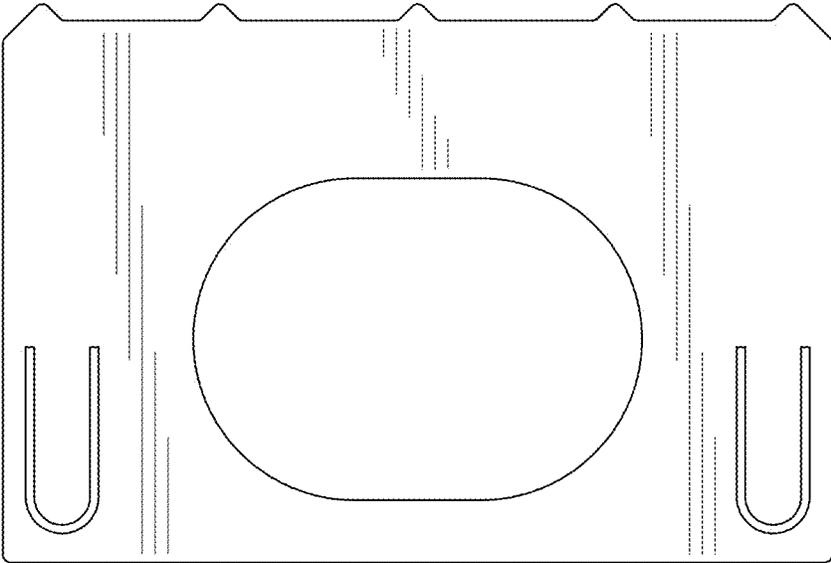


FIG. 4



FIG. 5



FIG. 6



FIG. 7

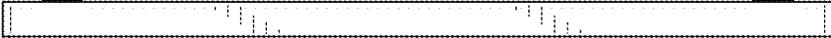


FIG. 8